

# Bachelor / Master Thesis

## Nanoscopic analysis of a mesoscopic tribological test

### Background:

Atomic force microscope (AFM) allows for surface characterization topographically and mechanically. It is of great importance to characterize the surface properties after tribological tests to have insight into the mechanisms of friction and wear.

### Project description:

- Nano-indentation on the wear track after a tribological test
- Analyzing mechanical properties of the wear track after different cycles of loading

### Qualification:

- Interest in advanced material testing methods
- Independence, reliability

### We offer:

- Intensive support and supervision
- Cutting-edge topic
- Modern processing methods

### Interested?

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